FAIRCHILD

SEMICONDUCTOR TM

November 1998

FDG6321C Dual N & P Channel Digital FET

General Description

These dual N & P-Channel logic level enhancement mode field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance. This device has been designed especially for low voltage applications as a replacement for bipolar digital transistors and small signal MOSFETS. Since bias resistors are not required, this dual digital FET can replace several different digital transistors, with different bias resistor values.

Features

- N-Ch 0.50 A, 25 V, $R_{\rm DS(ON)} = 0.45 \ \Omega \ @ V_{\rm GS} = 4.5 V.$ $R_{\rm DS(ON)} = 0.60 \ \Omega \ @ V_{\rm GS} = 2.7 \ V.$
- P-Ch -0.41 A, -25 V, $R_{DS(ON)} = 1.1 \Omega @ V_{GS} = -4.5V.$ $R_{DS(ON)} = 1.5 \Omega @ V_{GS} = -2.7V.$
- Very small package outline SC70-6.
- Very low level gate drive requirements allowing direct operation in 3 V circuits(V_{GS(th)} < 1.5 V).
- Gate-Source Zener for ESD ruggedness (>6kV Human Body Model).

415

*						
SC70	6	SOT-23	SuperSOT [™] -6	SOT-8	SO-8	SOIC-14
	D1	G2 S2 C1 S1 G1	2			
Absolu	SC7(ute Maxin	J-6	$\Gamma_{A} = 25^{\circ}$ C unless otherwise r			
		num Ratings	$\Gamma_{A} = 25^{\circ}$ C unless otherwise r		P-Channel	Units
Symbol	ute Maxin Paramete	num Ratings	$\Gamma_{A} = 25^{\circ}$ C unless otherwise r	noted		Units V
Symbol V _{DSS}	ute Maxin Paramete Drain-Sour	num Ratings	Γ _A = 25°C unless otherwise r	noted N-Channel	P-Channel	
Symbol V _{DSS} V _{GSS}	ute Maxin Paramete Drain-Sour	num Ratings		noted N-Channel 25	P-Channel -25	V
Symbol V _{DSS} V _{GSS}	Paramete Drain-Sou Gate-Sour	num Ratings		noted N-Channel 25 8	P-Channel -25 -8	V V
Symbol V _{DSS} V _{GSS} I _D	Paramete Drain-Sour Gate-Sour Drain Cur	num Ratings T r rce Voltage ce Voltage rent - Continuous		noted N-Channel 25 8 0.5	P-Channel -25 -8 -0.41	V V
Absolu Symbol V _{DSS} V _{GSS} I _D P _D T _J ,T _{STG}	Paramete Drain-Sour Gate-Sour Drain Cur Maximum	num Ratings	(Note 1)	noted N-Channel 25 8 0.5	P-Channel -25 -8 -0.41 -1.2	V V A

Thermal Resistance, Junction-to-Ambient (Note 1)

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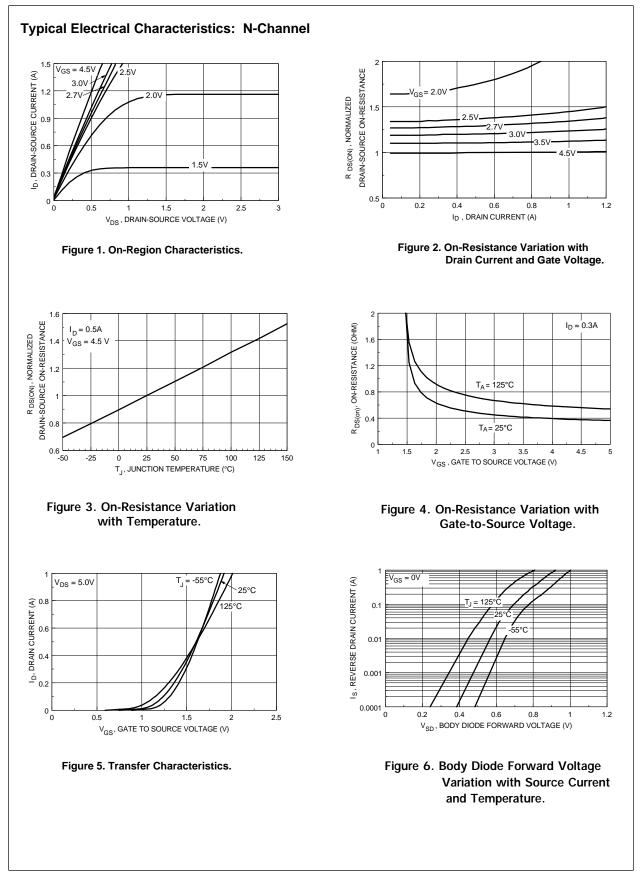
 $R_{\theta JA}$

°C/W

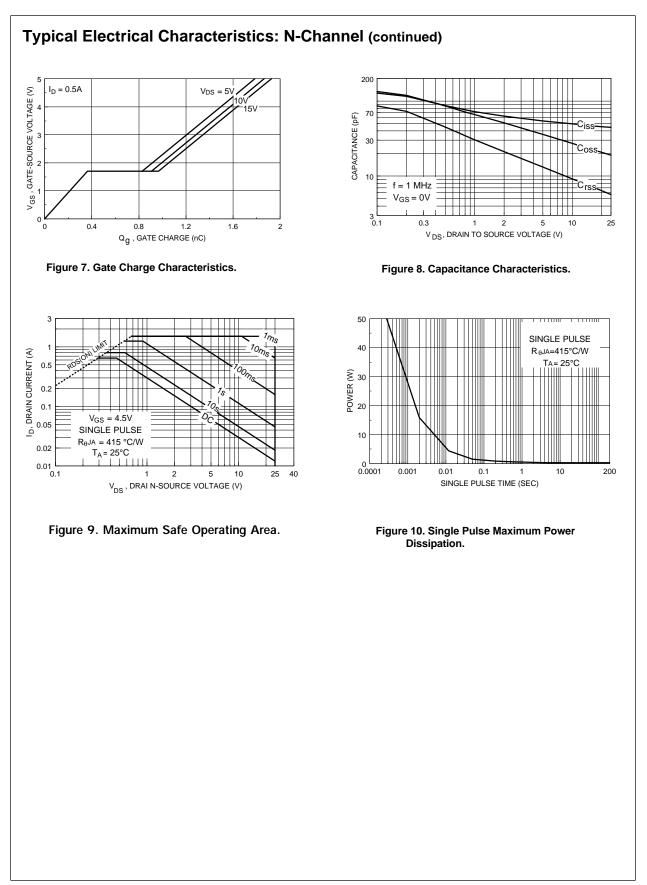
Symbol	Parameter	Conditions	Туре	Min	Тур	Max	Units
OFF CHAR	ACTERISTICS		51			1	
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_{D} = 250 \mu A$	N-Ch	25			V
000		$V_{gs} = 0 \text{ V}, \text{ I}_{p} = -250 \mu\text{A}$	P-Ch	-25			
$\Delta BV_{DSS} / \Delta T_{J}$	Breakdown Voltage Temp. Coefficient	$I_p = 250 \mu$ A, Referenced to 25 °C	N-Ch		26		mV/°C
Dss J		$I_{\rm p}$ = -250 µA, Referenced to 25 °C	P-Ch		-22		1
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 20 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	N-Ch			1 µ/	μA
		T _J = 55°C				10	
I _{GSS}	Gate - Body Leakage Current	$V_{ps} = -20 \text{ V}, \text{ V}_{qs} = 0 \text{ V}$	P-Ch			-1	μA
	, ,	T ₁ = 55°C				-10	
GSS	Gate - Body Leakage Current	$V_{GS} = 8 V, V_{DS} = 0 V$	N-Ch			100	nA
635	, ,	$V_{gs} = -8 V, V_{Ds} = 0 V$	P-Ch			-100	nA
ON CHARA	CTERISTICS (Note 2)	GS DS					ļ
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	N-Ch	0.65	0.8	1.5	V
GS(III)	5	$V_{\rm DS} = V_{\rm GS}, \ I_{\rm D} = -250 \mu {\rm A}$	P-Ch	-0.65	-0.82	-1.5	
$\Delta V_{GS(th)} / \Delta T_J$	Gate Threshold Voltage Temp. Coefficient	$I_p = 250 \mu$ A, Referenced to $25 ^{\circ}$ C	N-Ch		-2.6		mV/ °C
GS(th) GS(th)	5 1	$I_p = -250 \ \mu$ A, Referenced to 25 °C	P-Ch		2.1		
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 4.5 \text{ V}, I_{D} = 0.5 \text{ A}$	N-Ch		0.34	0.45	Ω
DS(ON)		T_ =125°C			0.55	0.72	
		$V_{gs} = 2.7 \text{ V}, I_{p} = 0.2 \text{ A}$			0.44	0.6	
		$V_{GS} = -4.5 \text{ V}, \text{ I}_{D} = -0.41 \text{ A}$	P-Ch		0.85	1.1	
		T _J =125°C			1.2	1.8	
		$V_{gs} = -2.7 \text{ V}, I_{p} = -0.25 \text{ A}$			1.15	1.5	
D(ON)	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$	N-Ch	0.5			Α
D(ON)		$V_{GS} = -4.5 \text{ V}, V_{DS} = -5 \text{ V}$	P-Ch	-0.41			
9 _{FS}	Forward Transconductance	$V_{DS} = 5 \text{ V}, \text{ I}_{D} = 0.5 \text{ A}$	N-Ch		1.45		S
		$V_{\rm DS} = -5 \text{ V}, \text{ I}_{\rm D} = -0.41 \text{ A}$	P-Ch		0.9		
	CHARACTERISTICS		1				1
C _{iss}	Input Capacitance	N-Channel	N-Ch		50		pF
100		$V_{DS} = 10 \text{ V}, \text{ V}_{GS} = 0 \text{ V},$	P-Ch		62		
C _{oss}	Output Capacitance	f = 1.0 MHz	N-Ch		28		
		P-Channel	P-Ch		34		
C _{rss}	Reverse Transfer Capacitance	$V_{\rm DS} = -10 \text{ V}, V_{\rm GS} = 0 \text{ V},$	N-Ch		9		
		f = 1.0 MHz	P-Ch		10		

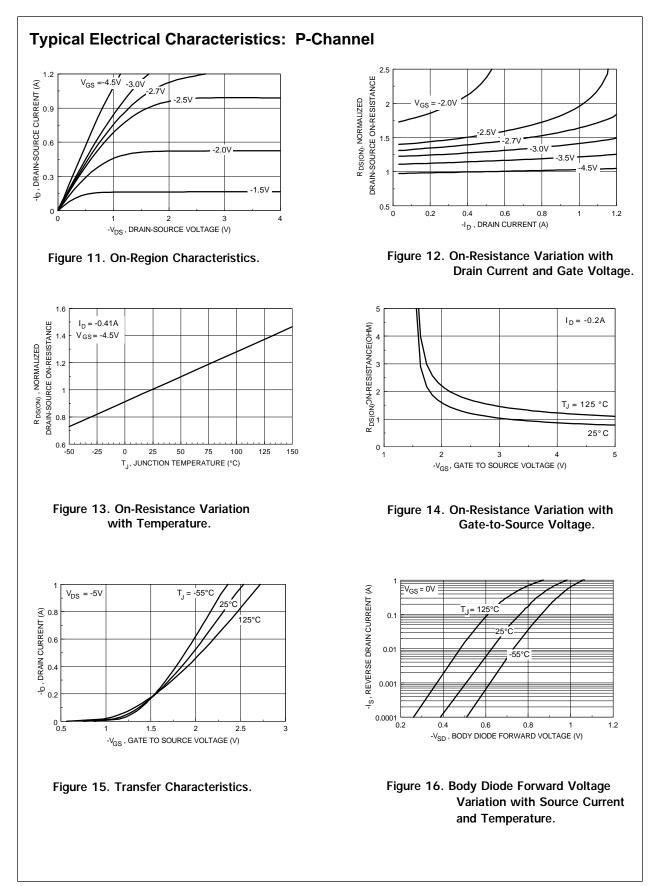
SWITCHI	NG CHARACTERISTICS (Note 2)						
Symbol	Parameter	Conditions	Туре	Min	Тур	Max	Units
t _{D(on)}	Turn - On Delay Time	N-Channel	N-Ch		3	6	nS
		$V_{DD} = 5 \text{ V}, \text{ I}_{D} = 0.5 \text{ A},$	P-Ch		7	15	
t,	Turn - On Rise Time	$\rm V_{GS}{=}$ 4.5 V, $\rm R_{GEN}{=}$ 50 Ω	N-Ch		8.5	18	nS
			P-Ch		8	16	
t _{D(off)}	Turn - Off Delay Time	P-Channel	N-Ch		17	30	nS
		$V_{DD} = -5 \text{ V}, \text{ I}_{D} = -0.5 \text{ A},$	P-Ch		55	80	
t _r	Turn - Off Fall Time	V_{GS} = -4.5 V, R_{GEN} = 50 Ω	N-Ch		13	25	nS
			P-Ch		35	60	
Q _q	Total Gate Charge	N-Channel	N-Ch		1.64	2.3	nC
		$V_{\rm DS} = 5 \text{ V}, \text{ I}_{\rm D} = 0.5 \text{ A},$	P-Ch		1.1	1.5	
Q _{gs}	Gate-Source Charge	$V_{GS} = 4.5 V$	N-Ch		0.38		nC
		P- Channel	P-Ch		0.31		
Q_{gd}	Gate-Drain Charge	$V_{\rm DS} = -5 \ V, \ I_{\rm D} = -0.41 \ A,$	N-Ch		0.45		nC
		V _{GS} = -4.5 V	P-Ch		0.29		
DRAIN-SC	OURCE DIODE CHARACTERISTICS AND	MAXIMUM RATINGS					
I _s	Maximum Continuous Drain-Source Diode Forward Current					0.25	А
			P-Ch			-0.25	
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, \ I_{S} = 0.5 \text{ A} \ (\text{Note 2})$	N-Ch		0.8	1.2	V
		$V_{GS} = 0 V, I_{S} = -0.5 A$ (Note 2)	P-Ch		-0.85	-1.2	

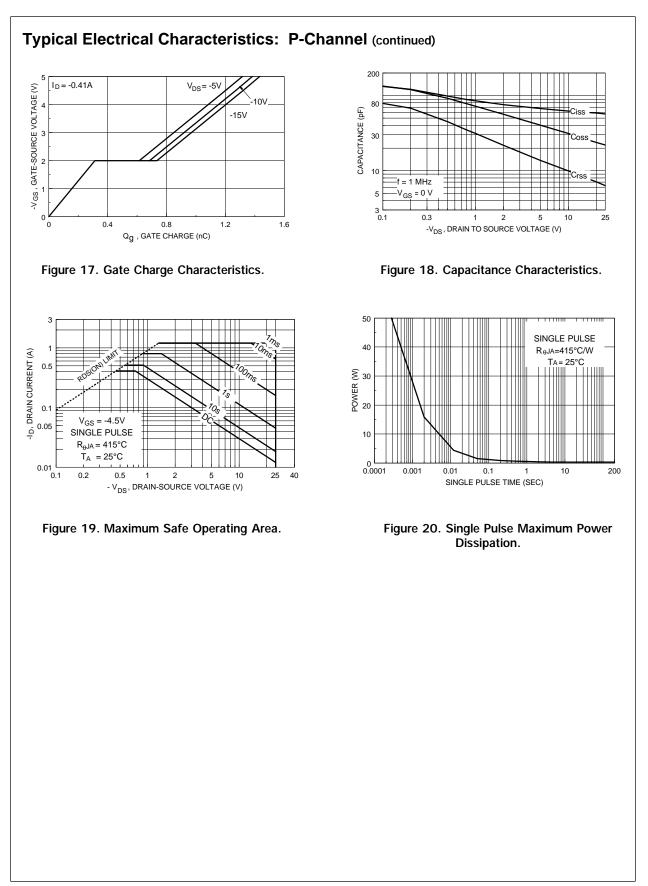
1. R_{BM} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BC} is guaranteed by design while R_{ack} is determined by the user's board design. $R_{a_{B,N}} = 415^{\circ}$ C/W on minimum mounting pad on FR-4 board in still air. 2. Pulse Test: Pulse Width $\leq 300\mu$ s, Duty Cycle $\leq 2.0\%$.

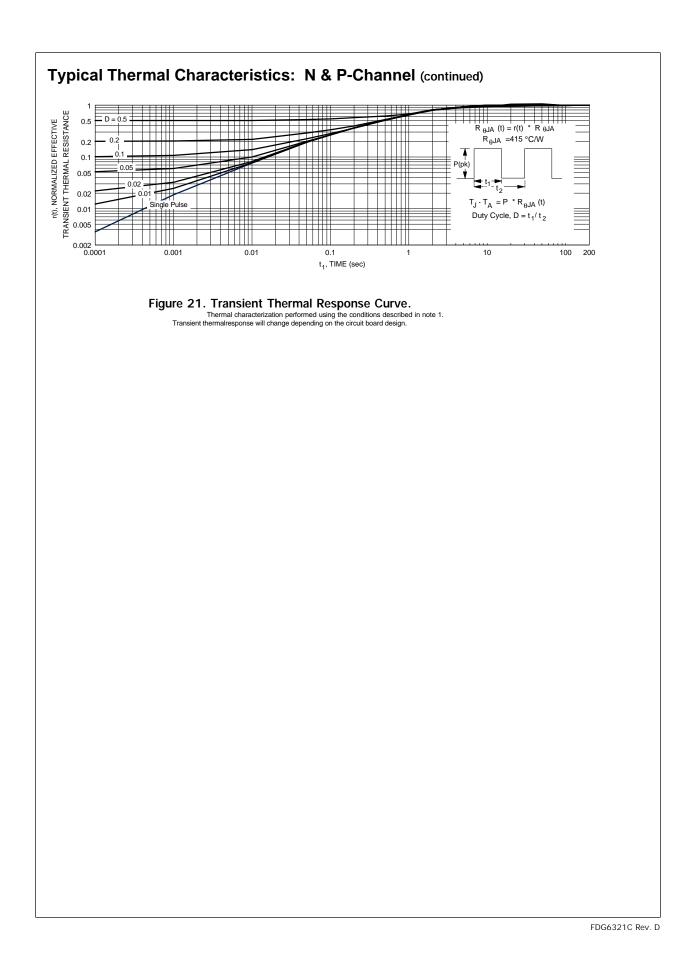


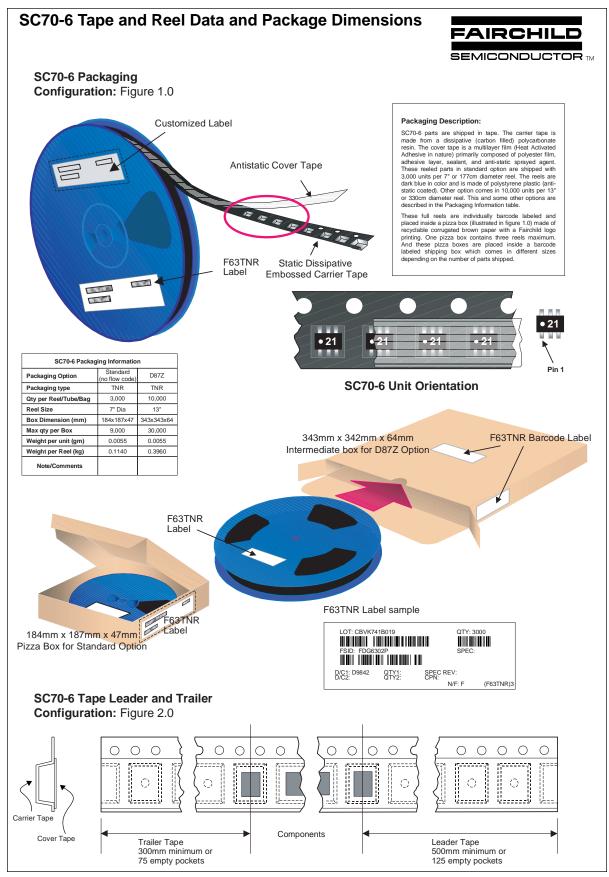
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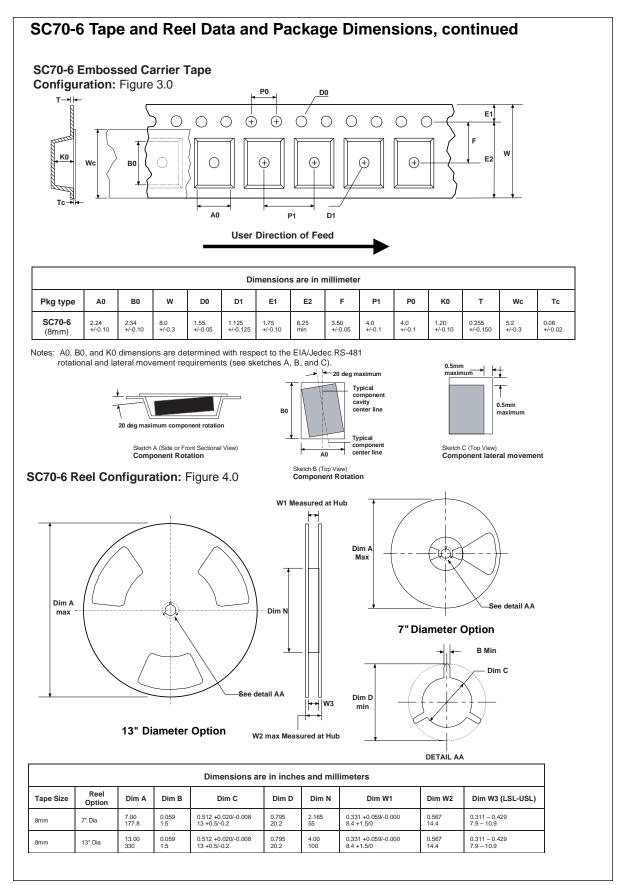


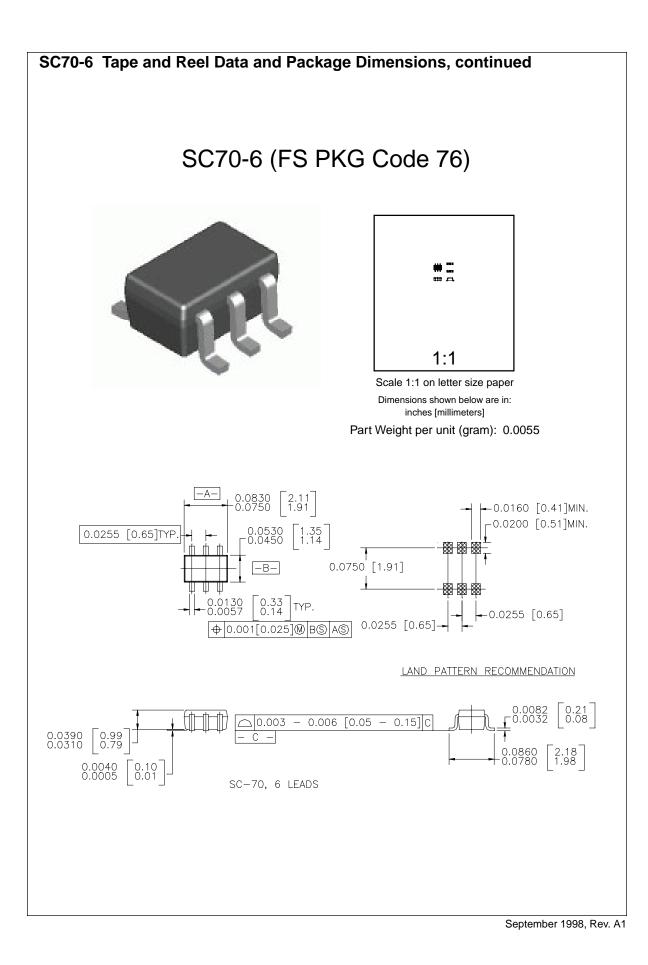






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